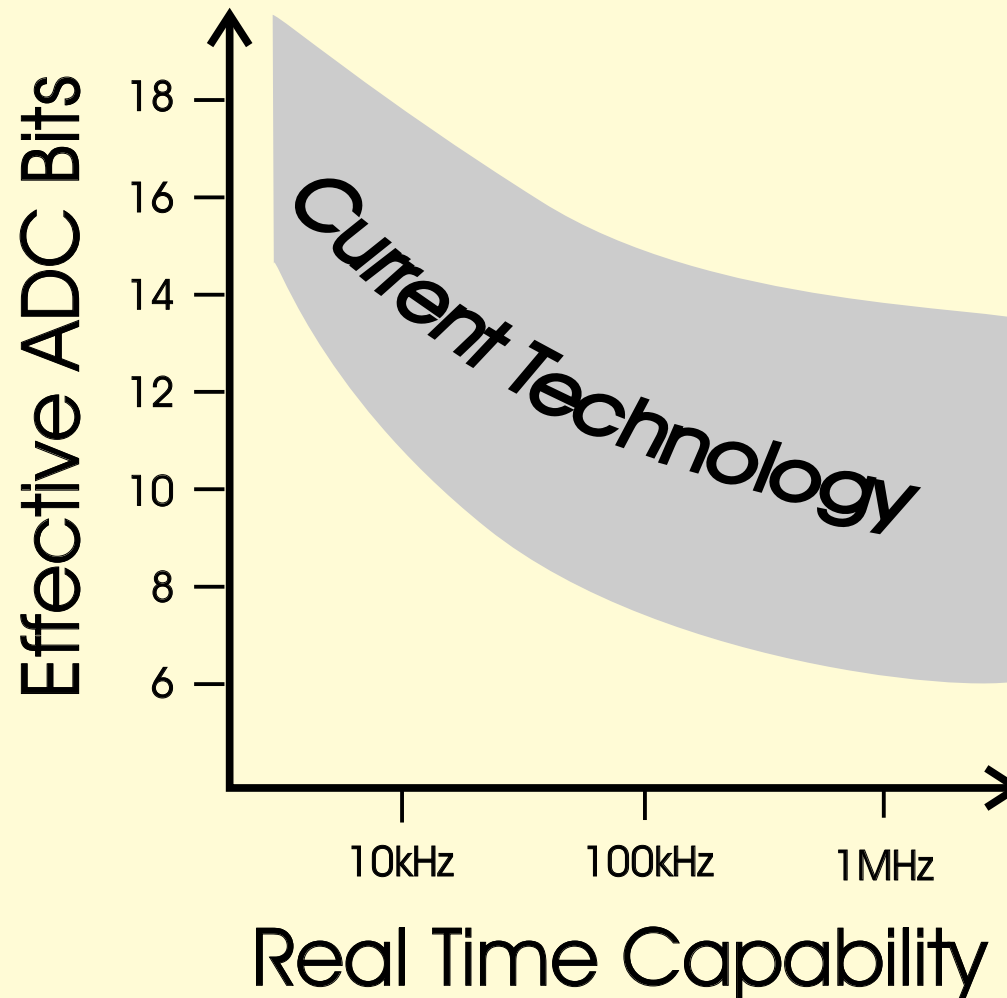


Association of Old Crows
31st Annual AOC EW Technical Symposium

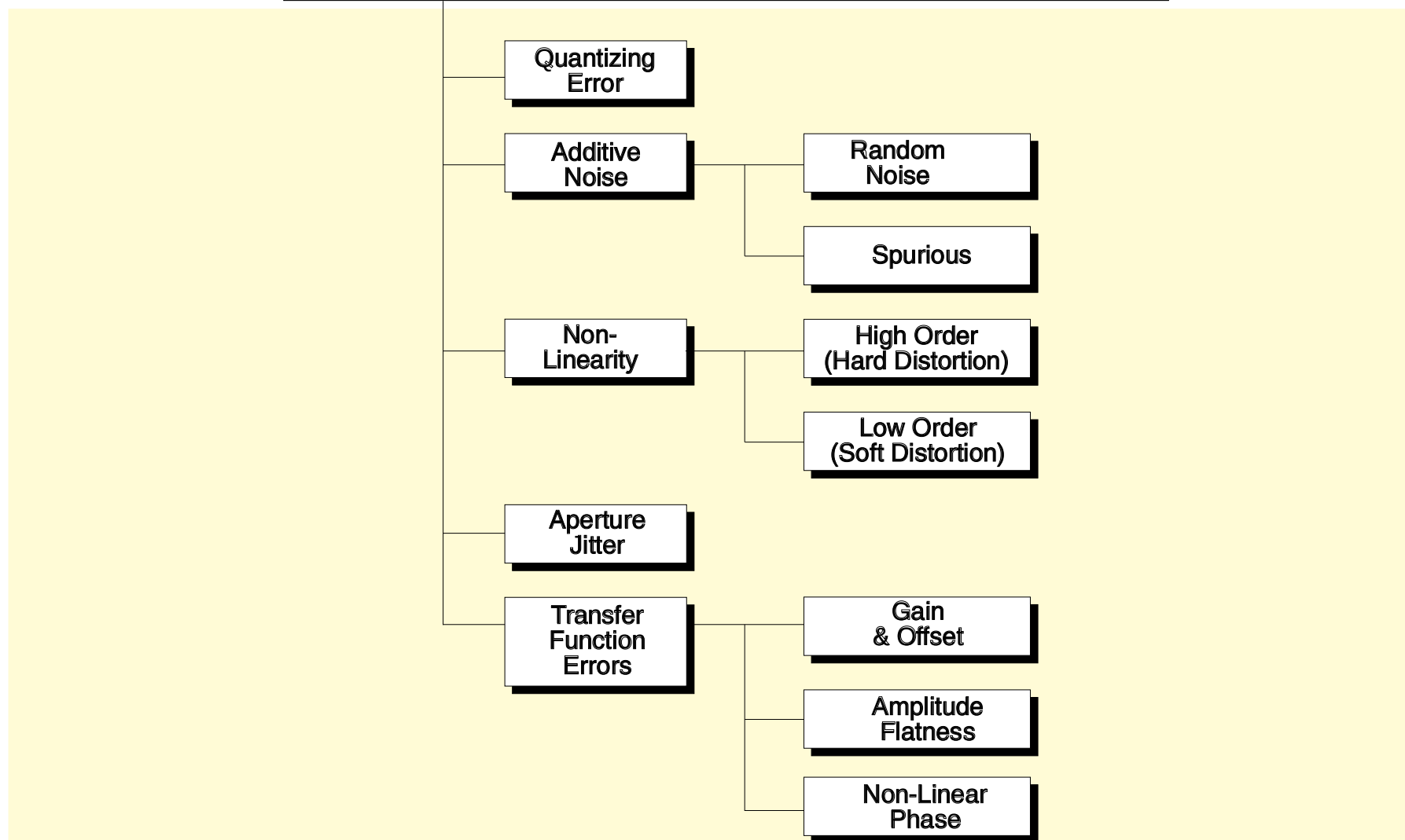
A Digital Signal Processing Approach to Analog-to-Digital Conversion

Allen W. Alexopoulos
Hewlett-Packard Company
October 10, 1994
Washington, DC

ADC Effective Bit Performance



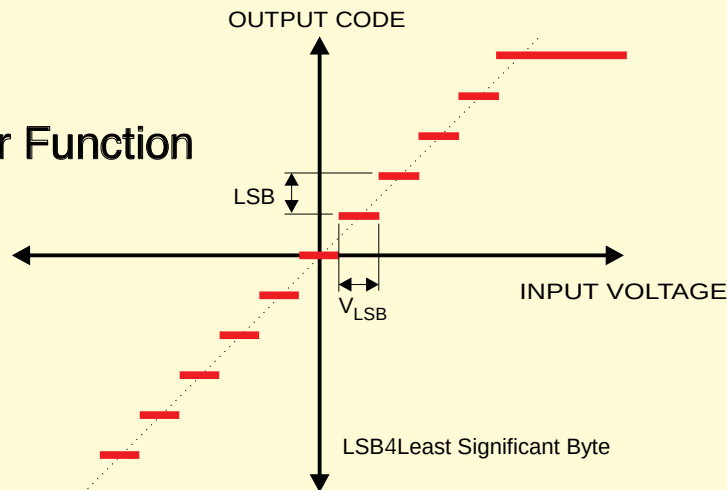
ADC Error Sources



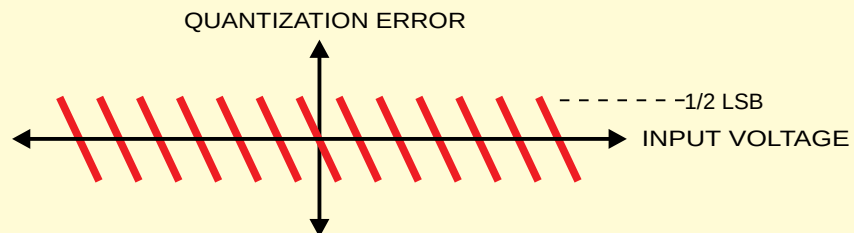
ADC Error Sources

Quantizing Error

Ideal Quantizer Transfer Function



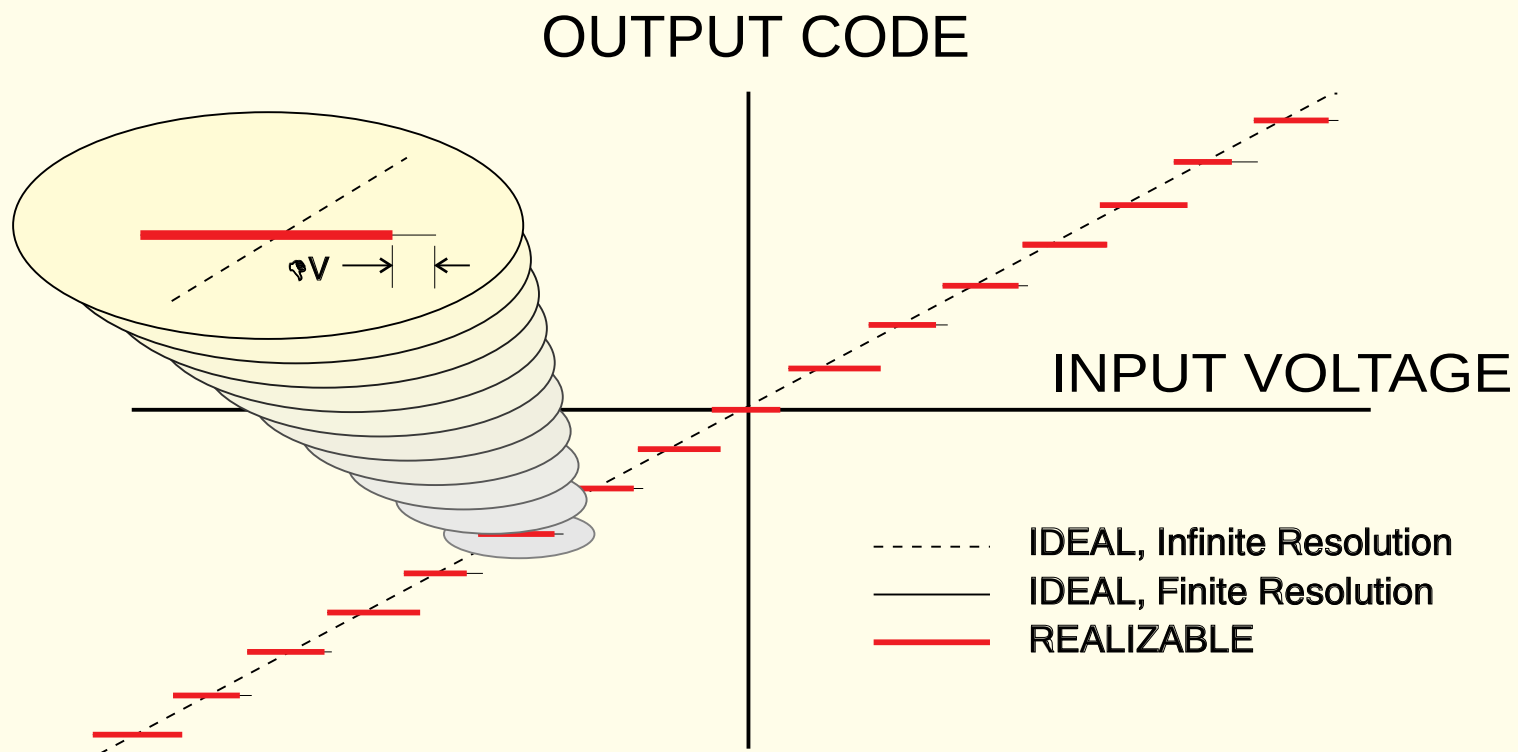
Quantizing Error for an Ideal ADC



ADC Error Sources

Non-
Linearity

Quantizer Differential Non-Linearity

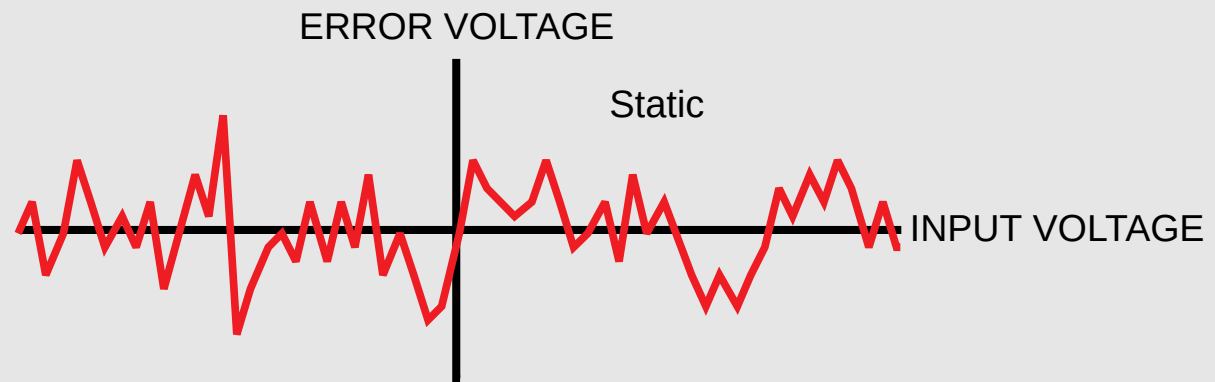


ADC Error Sources

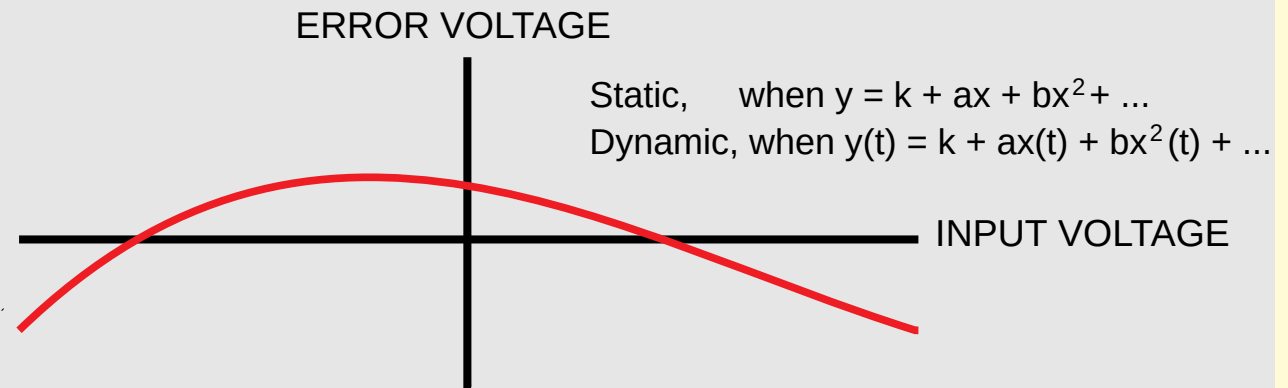
Non-
Linearity

NON-LINEARITIES

"Hard"
Distortion
(HIGH ORDER)

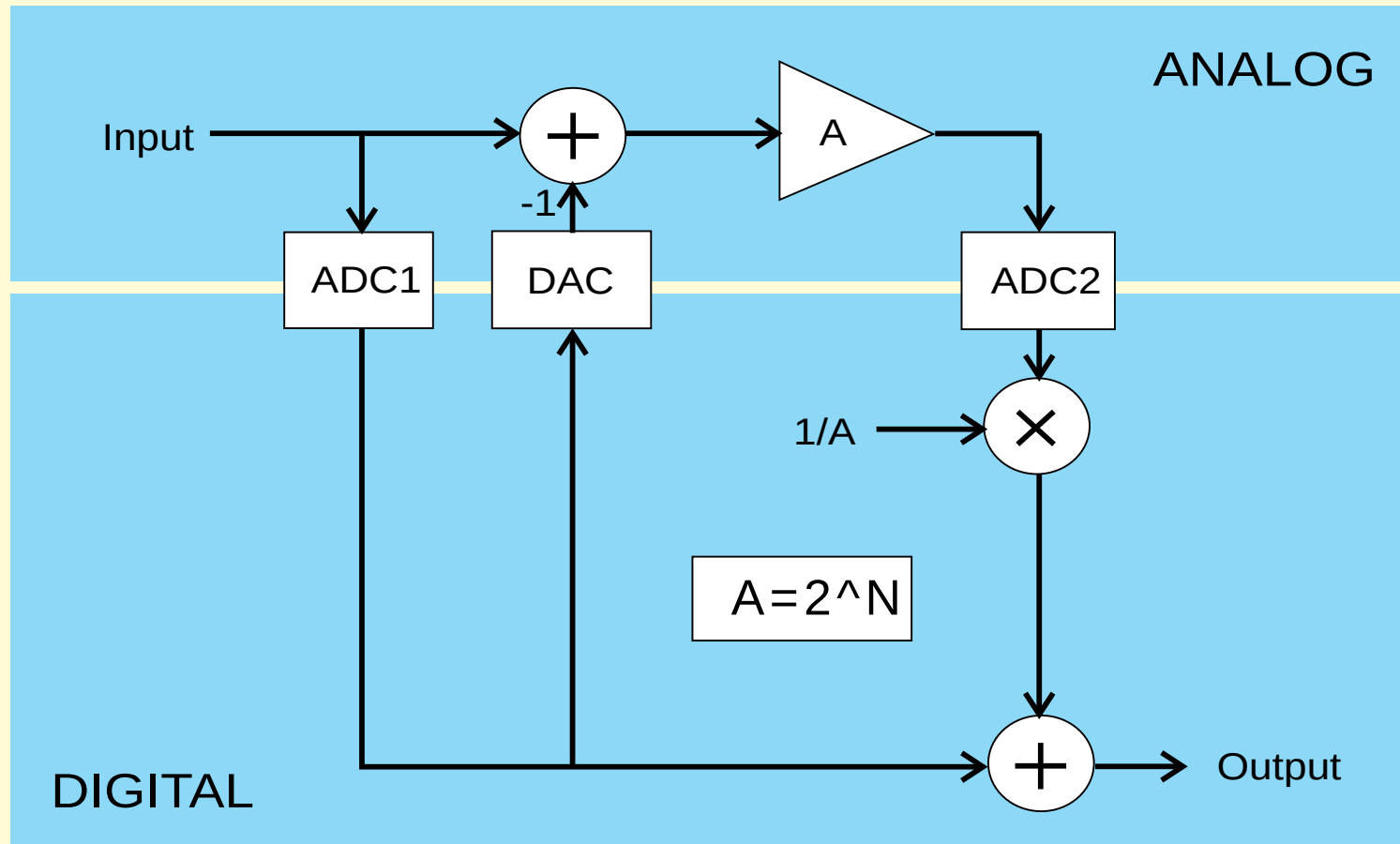


"Soft"
Distortion
(LOW ORDER)

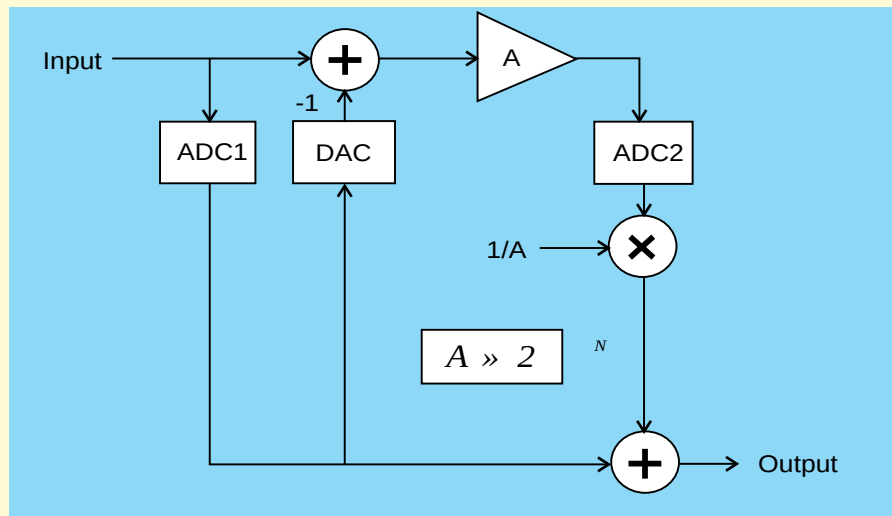


Standard 2-Pass ADC

The "Subranging Converter"



Standard 2-Pass ADC

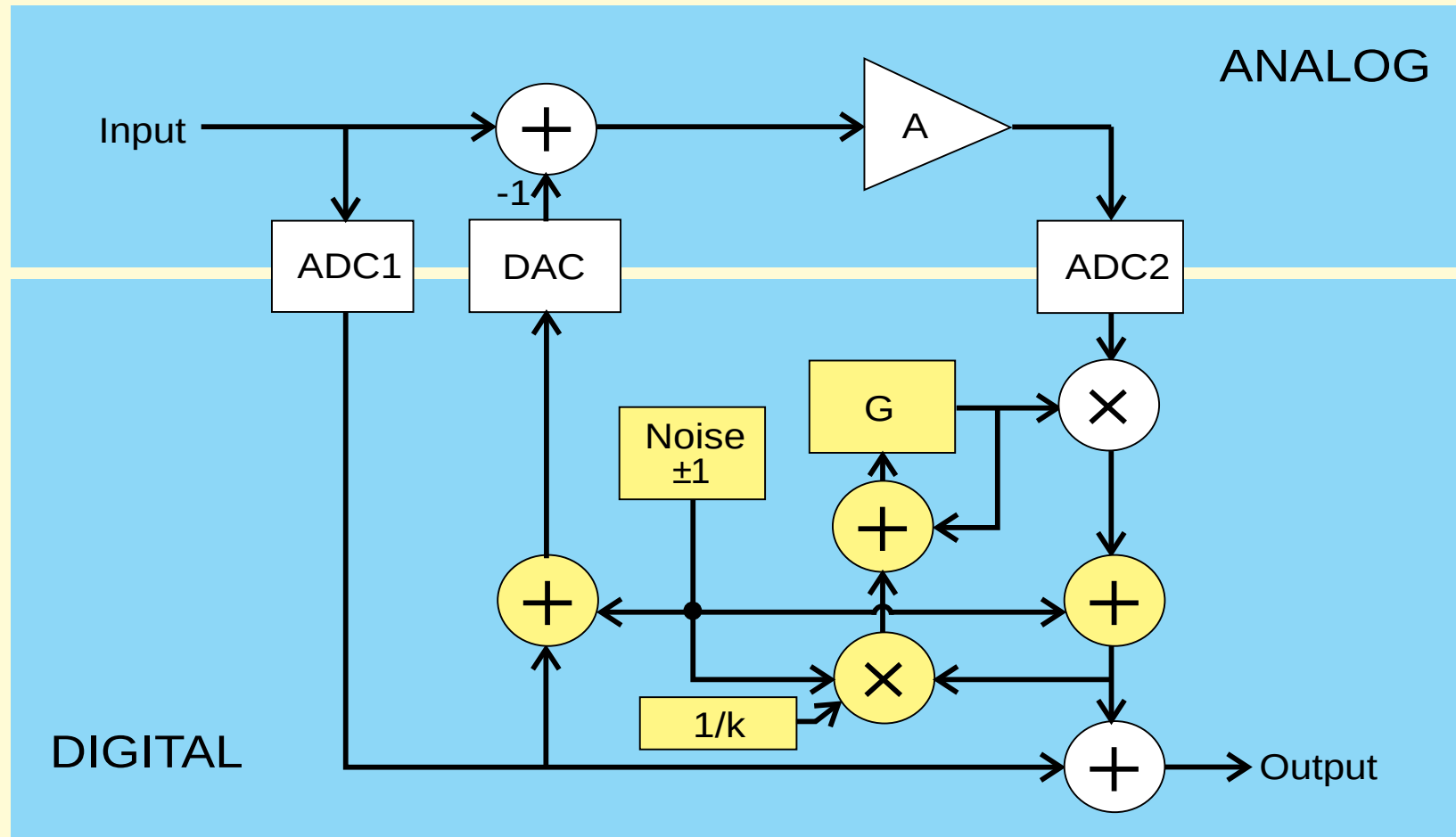


X - Input from track & hold
 Y - Output sample
 E_1 - ADC1 quantization error
 E_2 - ADC2 quantization error
 E_d - DAC error

$$Y \equiv X + E_1(1 - A2^{-N}) + E_d A 2^{-N} + E_2 2^{-N}$$

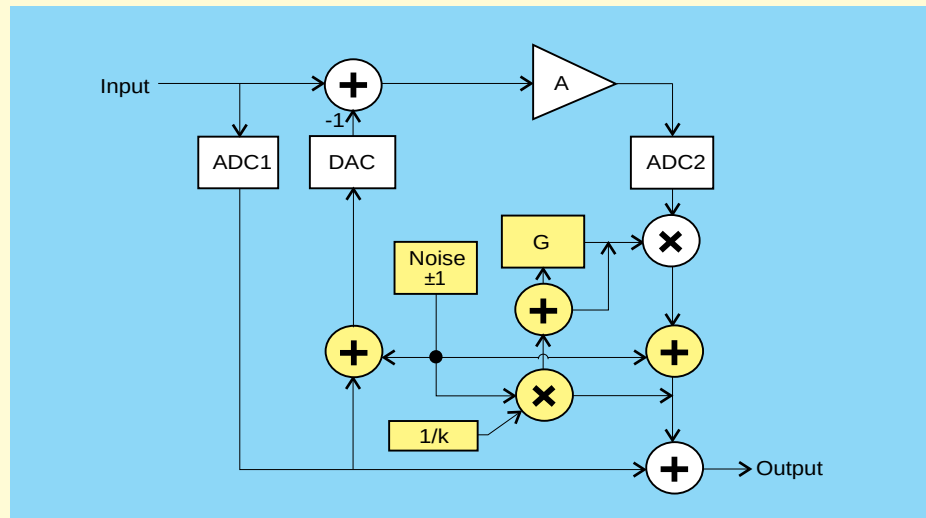
Enhanced 2-Pass ADC

Statistically-based continuous calibration



Enhanced 2-Pass ADC

Calibration of Residue Gain



X_n - Input from track & hold

G_n - Gain value

N_n - Random ± 1 sequence

D_n - Output of ADC1

A - Residue amplifier gain

$$G_{n+1} \equiv G_n \mp \frac{N_n}{k} (AG_n(X_n - D_n - N_n) \mp N_n)$$

$$G_{n+1} \equiv G_n \mp \frac{1}{k} (1 - AG_n) \quad \text{Difference equation}$$

$$G_n \equiv \frac{1}{A} \mp \left(1 - \frac{A}{k}\right)^n \left(G_0 - \frac{1}{A}\right) \quad \text{Exponential Average}$$

Closed-loop system
tracks changes in
residue amp gain!

$$G_{\odot} \equiv \frac{1}{A}$$

Enhanced 2-Pass ADC

Standard 2-Pass Error Model

$$Y \equiv X + E_1(1 - AG) + E_dAG + E_2G$$

Contribution of Gain Calibration

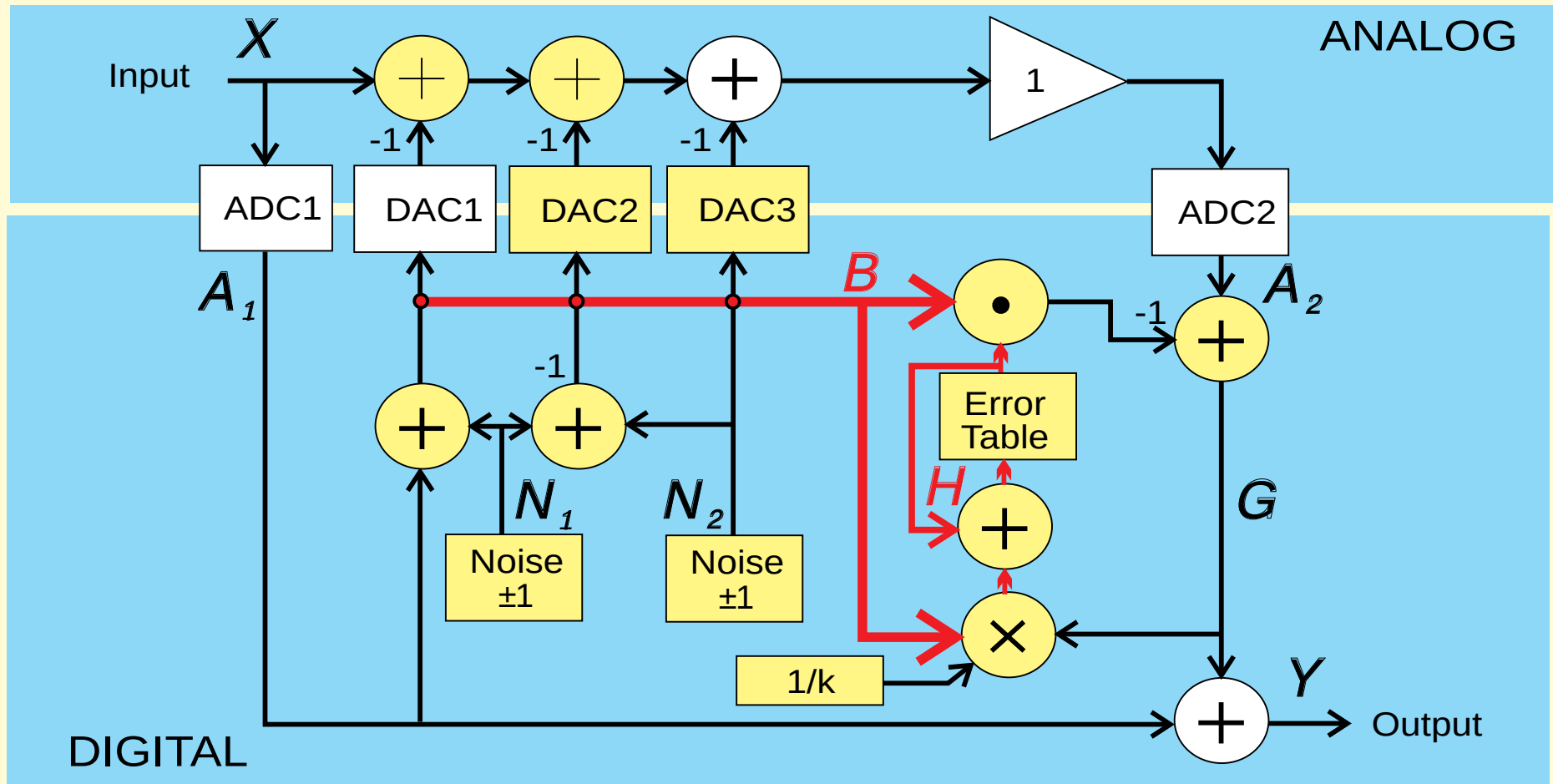
$$G \equiv \frac{1}{A}$$

New Error Model

$$Y \equiv X + E_d + \frac{E_2}{A}$$

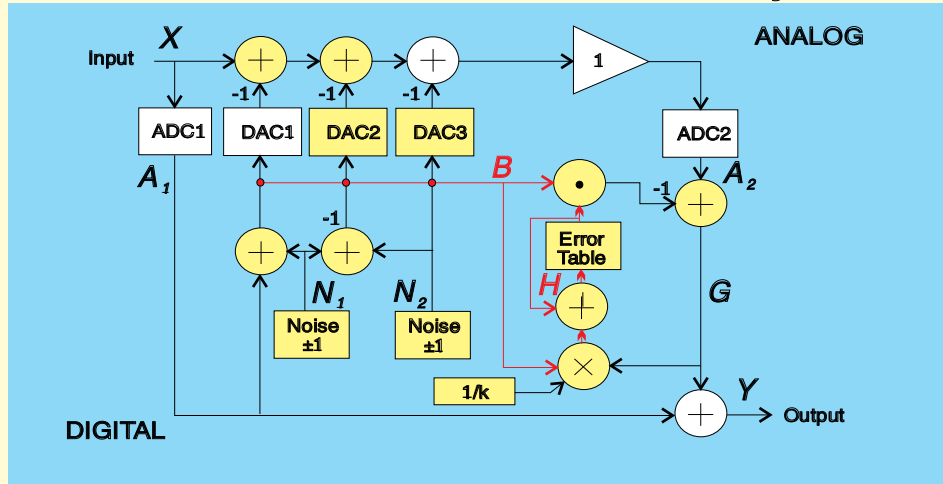
Enhanced 2-Pass ADC

Statistically-based DAC calibration



Enhanced 2-Pass ADC

Statistically-based DAC calibration



- B** - Vector of DAC bit line states
- b_n - MSB of DAC1
- C** - Vector with DAC bit weights w/errors
- H** - Vector with corrections for DAC bit errors
- W** - Vector, Expected Value($\mathbf{C} + \mathbf{H}_n$)
- D** - Vector, Expected Value($\mathbf{B}_n b_n$)
- F** - Matrix, Expected Value($\mathbf{B}_n \mathbf{B}_n^T$)

$$\mathbf{G}_n \equiv \mathbf{X} - b_n - \mathbf{B}_n \odot \mathbf{C} \oplus \mathbf{B}_n \odot \mathbf{H}_n$$

$$\mathbf{H}_{n+1} \equiv \mathbf{H}_n \oplus \frac{\mathbf{B}_n}{k} (\mathbf{X} - b_n - \mathbf{B}_n^T (\mathbf{C} \oplus \mathbf{H}_n))$$

$$\mathbf{W}_n \equiv -\mathbf{F}_{-1} \mathbf{D} \oplus \left(\mathbf{I} - \frac{1}{k} \mathbf{F} \right)^n (\mathbf{W}_0 \oplus \mathbf{F}^{-1} \mathbf{D})$$

Closed-loop system
tracks and cancels
DAC bit current errors!

$$\mathbf{W}_\infty \equiv -\mathbf{F}^{-1} \mathbf{D}$$

Enhanced 2-Pass ADC

Dac calibration zeroes out the DAC error term E_d .

Model for ADC error after DAC calibration becomes:

$$Y = X + \frac{E_2}{A}$$

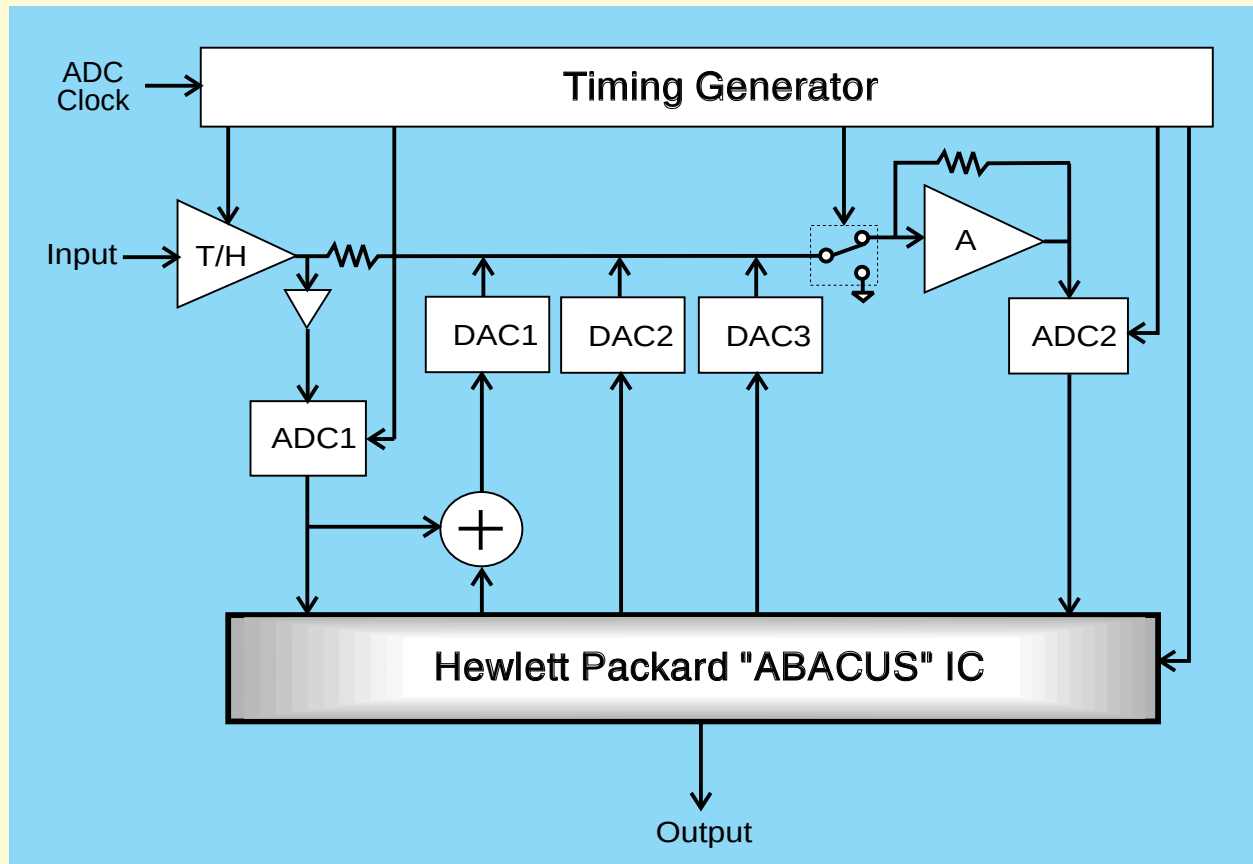
Analog dither at input of ADC2 and intentionally generated random errors from DAC3 cause 1/2 scale dither at input of ADC2. Remaining quantization noise goes away!

The Bottom Line!

$$Y_n \equiv X_n + noise_n$$

Enhanced 2-Pass ADC Implementation

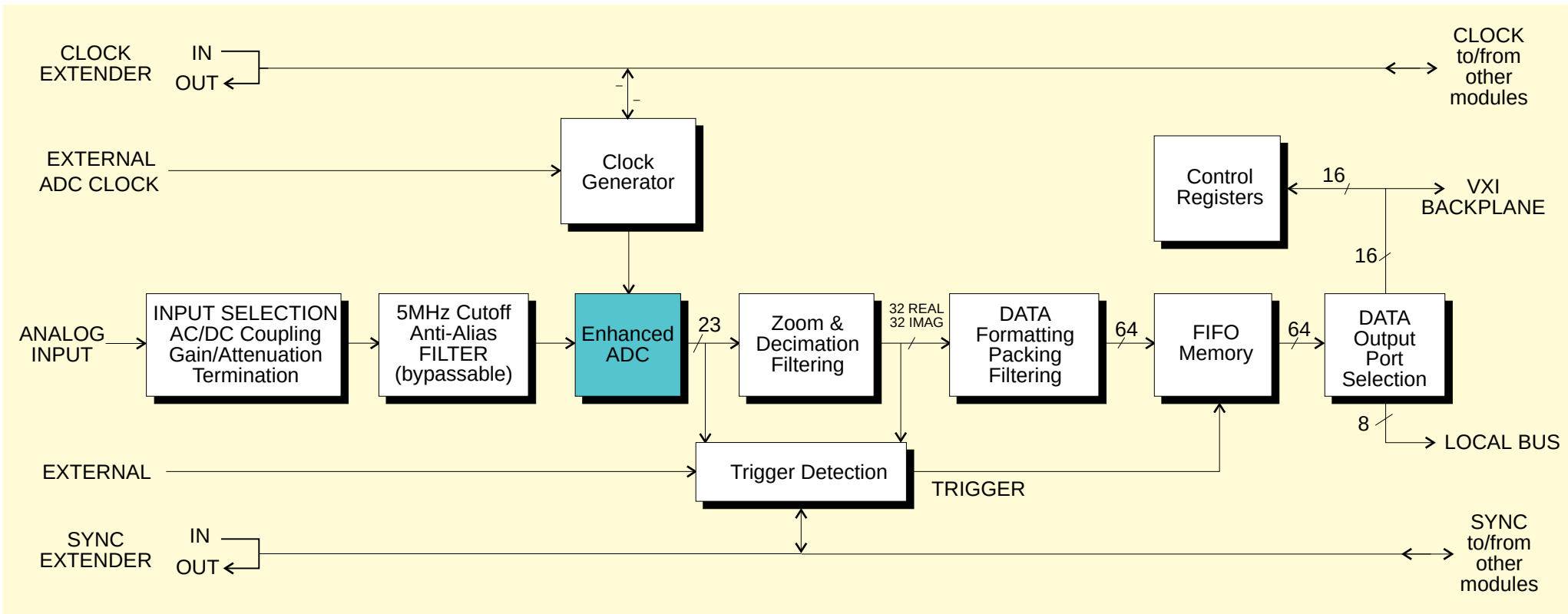
Enhanced ADC with 23-bit resolution



The "ABACUS" IC

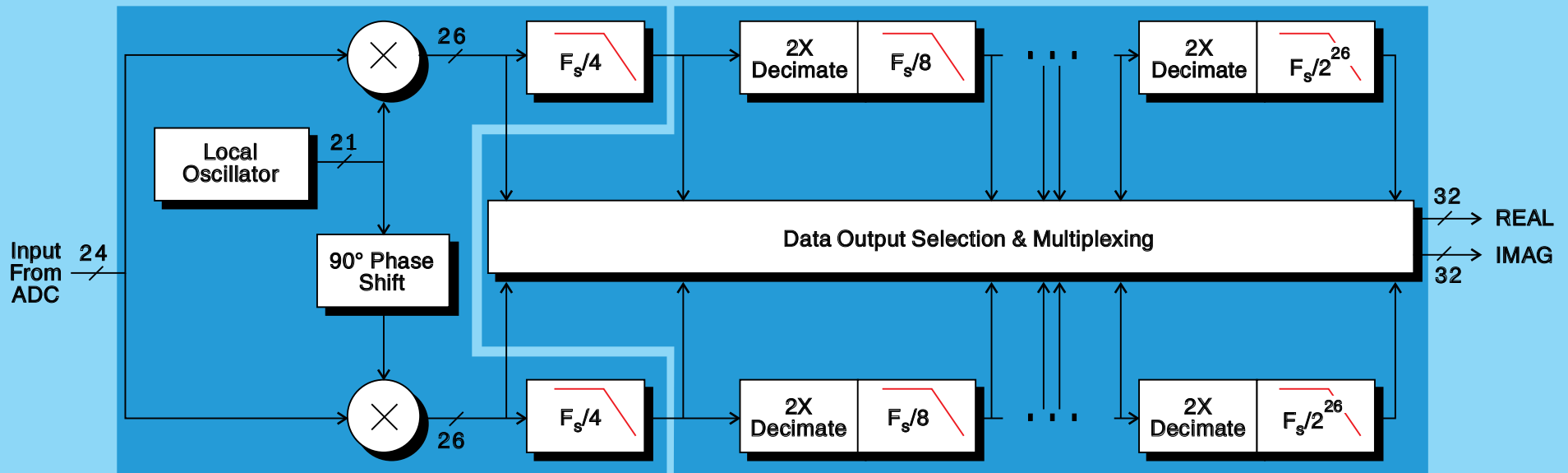
144-pin SM
CMOS-26 (≤ 0.9 micron)
 $\geq 200K$ transistors
REAL TIME up to 25MHz
Up to 9-bit ADC1, 12-bit ADC2
 $\geq 1.5G$ math ops/sec

Enhanced ADC-Based Front End



Design GOALS: 10MHz Sample Rate, -110dBSFDR, 23-bit Resolution
4MHz Bandwidth, 70dB SNR @ 10MSa/s

Zoom & Decimation Filtering



"Kestrel"

CMOS-26

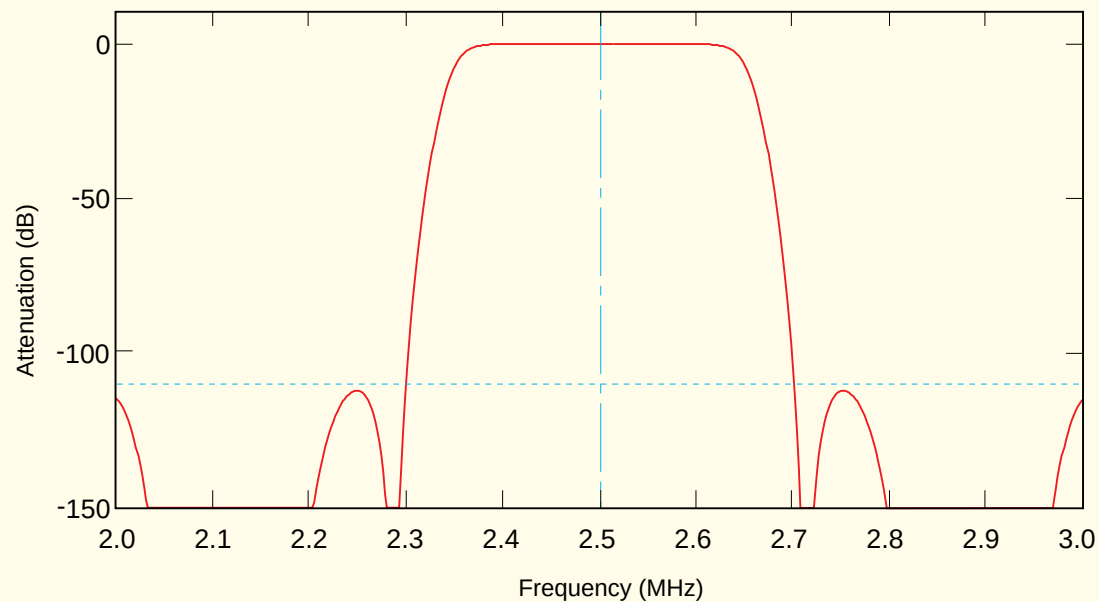
26MSa/s max REAL TIME rate
42 adds & 4 multiplies in parallel
1.196G ops/sec
Typical spurs $\leq -125\text{dBc}$

"Osprey"

CMOS-26

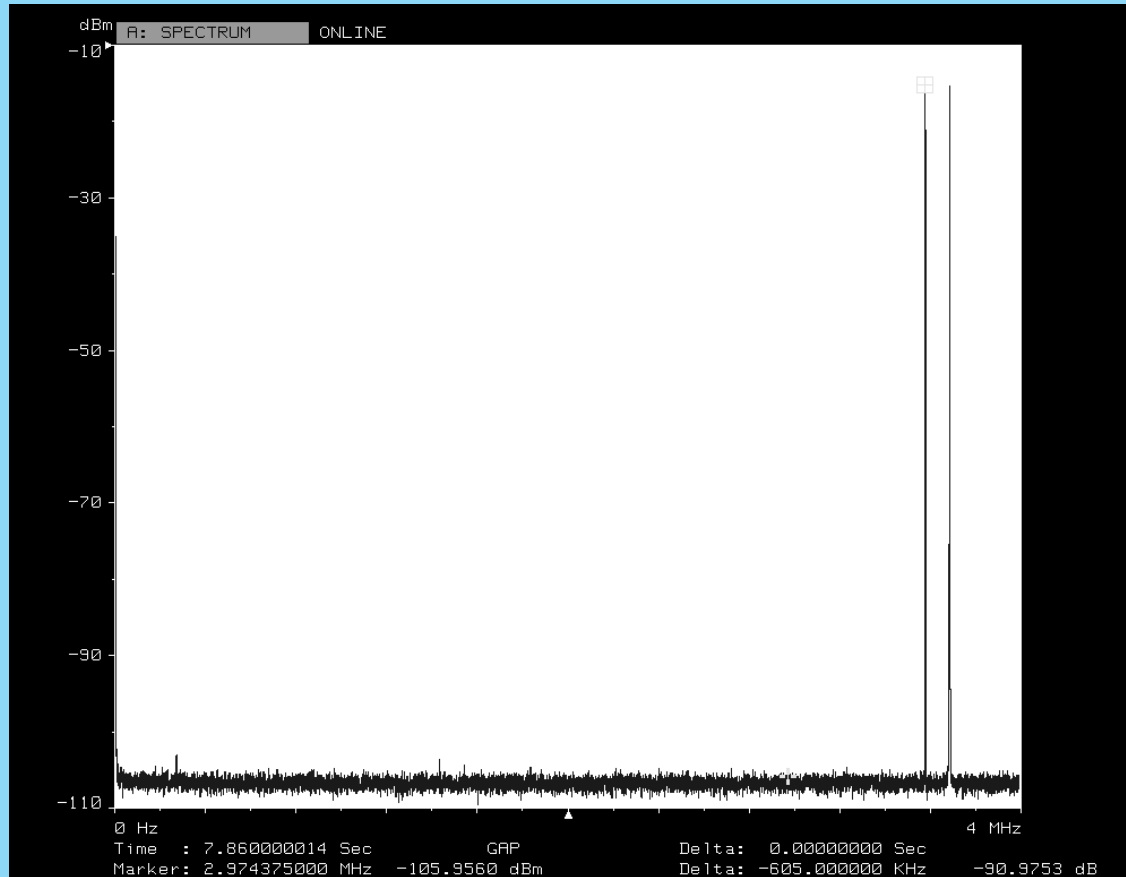
26MSa/s max REAL TIME rate
24x 15th order filters
520M ops/sec
Typical spurs $\leq -125\text{dBc}$

Digital Filter Magnitude Response



Magnitude Response of E1430A Digital Filter
(Zoom Mode, 5 Decimations)

2-Tone Intermodulation Example



Input Range: ± 4 dBm

Span: 4.00 MHz

Averages: 50 rms

Window: Hanning

Block Size: 32K sample

Bins: 12800

Bin Spacing: 312.5 Hz

ADC Error Sources

Non-
Linearity

SPECTRUM OF HIGH ORDER NON-LINEARITIES

OUTPUT FROM 10MHz, 70dB SNR ADC

8192 POINT FFT WITH P400 WINDOW

